

Current State of Domestic Heavy Ion Test Facilities

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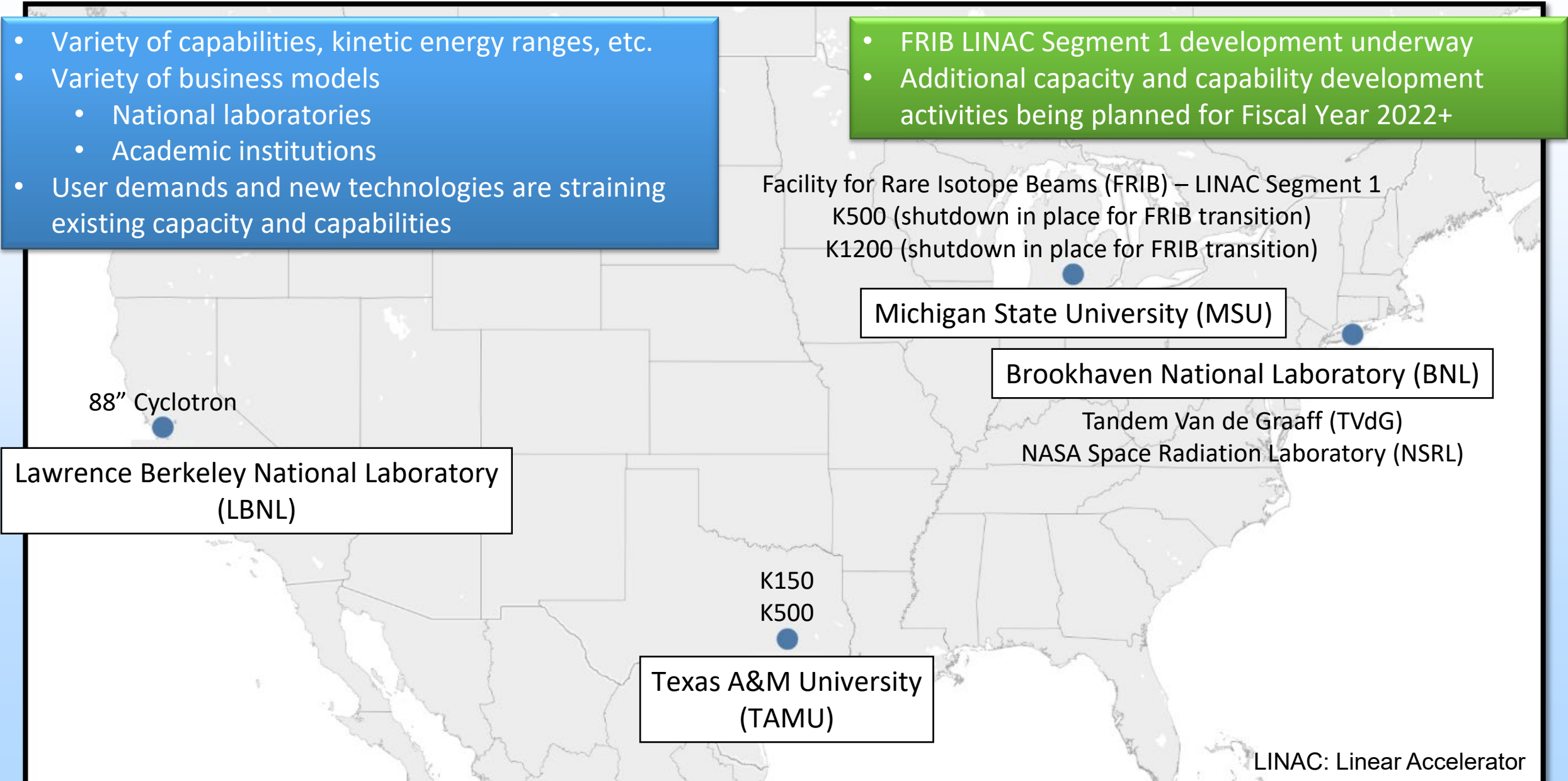
Abstract

We present the current status of United States domestic heavy ion single-event effects (SEE) radiation test facilities, including general perspectives on near- and mid-term needs for both capacity and capabilities.

Current United States Heavy Ion SEE Test Facilities

- Variety of capabilities, kinetic energy ranges, etc.
- Variety of business models
 - National laboratories
 - Academic institutions
- User demands and new technologies are straining existing capacity and capabilities

- FRIB LINAC Segment 1 development underway
- Additional capacity and capability development activities being planned for Fiscal Year 2022+



Lawrence Berkeley National Laboratory (LBNL)

Michigan State University (MSU)

Brookhaven National Laboratory (BNL)

Texas A&M University (TAMU)

LINAC: Linear Accelerator

Breaking Down Radiation Effects Caused by the Natural Space Radiation Environment

Ionizing Radiation Effects

Total Ionizing Dose (TID)

Total Non-Ionizing Dose (TNID)

Single-Event Effects (SEE)

Non-Destructive

Destructive

Primarily high-energy protons and heavy ions

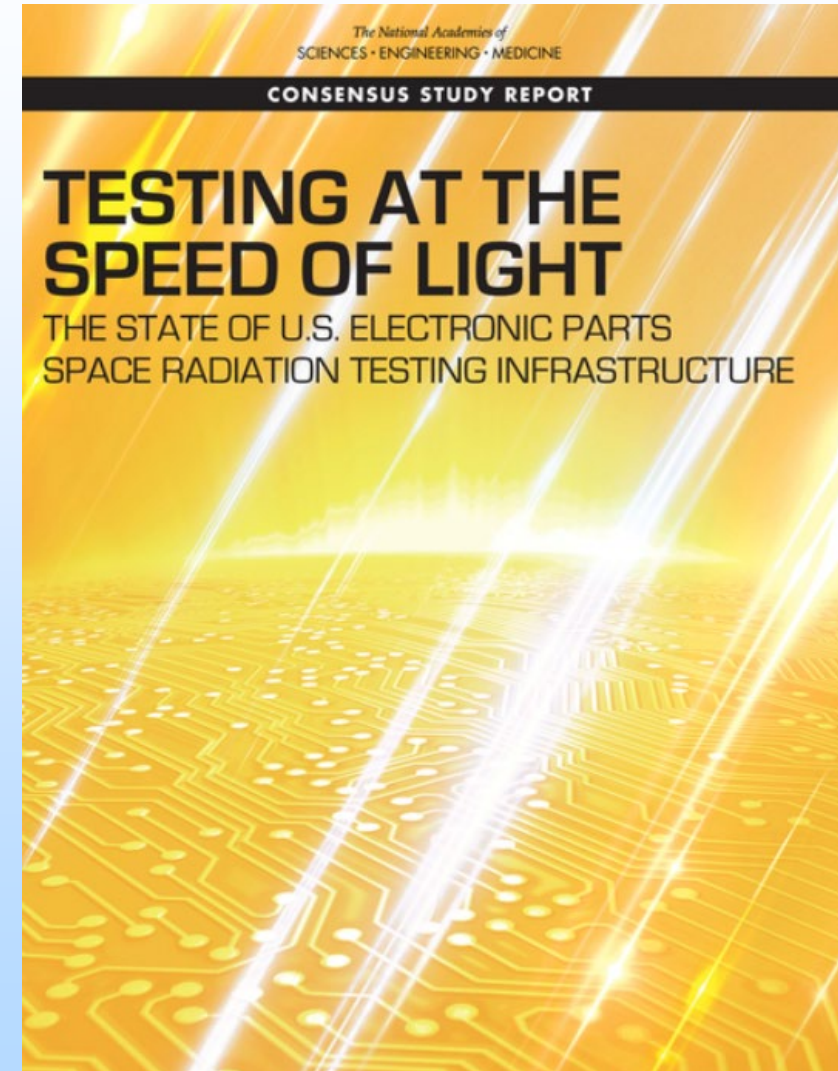
Not including charging

Why Perform SEE Testing?

- 1. To determine the presence and characteristics of single events**
 - Destructive or non-destructive?
 - Voltage- and/or temperature-dependent?
 - List goes on for a quite a while...
 - 2. To calculate bounding SEE rates as part of availability and/or reliability assessments for a given mission, environment, application, and lifetime (MEAL) – this is what matters to designers, system engineers, etc.**
- SEE testing is usually performed at **particle accelerator facilities**, which irradiate an electronic device target (or board or box) with high-energy ions.
 - **SEE test facilities are an essential part of the space industrial base.**

Recent Assessments – National Academies of Sciences, Engineering, and Medicine, 2018

- **Key findings**
 - Growing use and tightening supply
 - Infrastructure showing signs of strain
 - Aging workforce in a domain that requires specialized training and skills
 - Fast-moving technology
- **Points to / needs**
 - More organizational coordination
 - Test facility sustainment & new investments
 - Coupled with appropriate research & development
 - Workforce development
- **At least one detailed assessment pre-dated this work, Aerospace Corp. TOR-2015-00473.**



Recent Assessments – Analysis of Alternatives, 2019

- **Key findings**

- Existing heavy ion SEE test facilities cannot meet current or future SEE test demand (~5000 hour/year gap)
- Department of Defense efforts as well as U.S. Government and commercial space are driving significant increases in SEE testing demand
- Current heavy ion accelerators for SEE testing at U.S. universities and Department of Energy labs have limited capacity and capability
- More complex electronics require more test hours
- More advanced electronics and packaging require higher ion energies, >100 MeV/amu

Analysis of Alternatives Findings and Recommendations are Independent and Non-Binding



J. Franco & J. Ross, *Public Summary from Analysis of Alternatives for Domestic Single-Event Effects Test Facilities* (Meeting [URL](#), Slides [URL](#))

Recent Assessments – Analysis of Alternatives, 2019

- Demand for high-energy SEE testing is growing (projections only)

| <h2>Low Energy SEE Test 2020</h2> | <h2>High Energy SEE Test 2020</h2> |
|---|--|
| <ul style="list-style-type: none"> ▪ 90% of SEE test is Low Energy <ul style="list-style-type: none"> – 10-50 MeV/n (Mega-Electron Volts /n) | <ul style="list-style-type: none"> • 10% of SEE test is High Energy <ul style="list-style-type: none"> – >100 MeV/n |
| <h2>2030</h2> | <h2>2030</h2> |
| <ul style="list-style-type: none"> ▪ 60% of SEE test is Low Energy <ul style="list-style-type: none"> – Economical test for monolithic integrated circuits – Issues for flip-chip, stacked die, 2.5/3D packaging, and assemblies ▪ Access assured with low energy investments ▪ TAMU K500 & K150, LBNL, FRIB Lin Seg 1, and MSU K500 meet Low Energy demand | <ul style="list-style-type: none"> • 40% of SEE test is High Energy <ul style="list-style-type: none"> – New technology and CCA level testing will demand high energy – Economical for new technology • Access assured by high energy investment • 40% is ~4000 hours/yr <ul style="list-style-type: none"> – BNL AGS or MSU K1200 meets High Energy demand <p>AGS: Alternating Gradient Synchrotron</p> |

J. Franco & J. Ross, *Public Summary from Analysis of Alternatives for Domestic Single-Event Effects Test Facilities* (Meeting [URL](#), Slides [URL](#))